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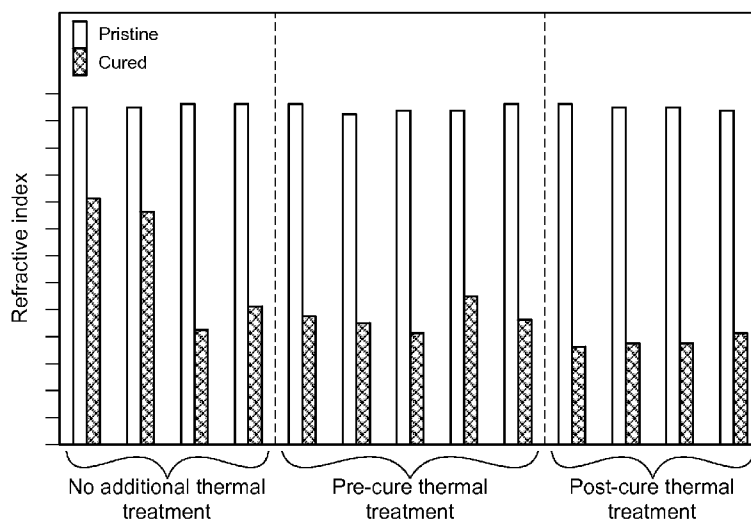


FIG. 2

(57) Abstract: A method of curing a low dielectric constant (low-k) dielectric film on a substrate is described, wherein the dielectric constant of the low-k dielectric film is less than a value of approximately 4. The method comprises exposing the low-k dielectric film to ultraviolet (UV) radiation. Following the UV exposure, the dielectric film is exposed to IR radiation.

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METHOD FOR CURING A DIELECTRIC FILM

CROSS-REFERENCE TO RELATED APPLICATIONS

[0001] This application is related to pending U.S. Patent Application No. 11/269,581, entitled "MULTI-STEP SYSTEM AND METHOD FOR CURING A DIELECTRIC FILM", filed on November 9, 2005, and pending U.S. Patent Application No. 11/269,581, entitled "THERMAL PROCESSING SYSTEM FOR CURING DIELECTRIC FILMS", filed on September 8, 2006. The entire contents of these applications are herein incorporated by reference in their entirety.

BACKGROUND OF THE INVENTION

FIELD OF THE INVENTION

[0002] The invention relates to a method for treating a dielectric film and, more particularly, to a method of curing a low dielectric constant (low-k) dielectric film and thermally treating the low-k dielectric film.

DESCRIPTION OF RELATED ART

[0003] As is known to those in the semiconductor art, interconnect delay is a major limiting factor in the drive to improve the speed and performance of integrated circuits (IC). One way to minimize interconnect delay is to reduce interconnect capacitance by using low dielectric constant (low-k) materials as the insulating dielectric for metal wires in the IC devices. Thus, in recent years, low-k materials have been developed to replace relatively high dielectric constant insulating materials, such as silicon dioxide. In particular, low-k films are being utilized for inter-level and intra-level dielectric layers between metal wires in semiconductor devices. Additionally, in order to further reduce the dielectric constant of insulating materials, material films are formed with pores, i.e., porous low-k dielectric films. Such low-k films can be deposited by a spin-on dielectric (SOD) method similar to the application of photo-resist, or by chemical vapor deposition (CVD). Thus, the use of low-k

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materials is readily adaptable to existing semiconductor manufacturing processes.

[0004] Low-k materials are less robust than more traditional silicon dioxide, and the mechanical strength deteriorates further with the introduction of porosity. The porous low-k films can easily be damaged during plasma processing, thereby making desirable a mechanical strengthening process. It has been understood that enhancement of the material strength of porous low-k dielectrics is essential for their successful integration. Aimed at mechanical strengthening, alternative curing techniques are being explored to make porous low-k films more robust and suitable for integration.

[0005] The curing of a polymer includes a process whereby a thin film deposited for example using spin-on or vapor deposition (such as chemical vapor deposition CVD) techniques, is treated in order to cause cross-linking within the film. During the curing process, free radical polymerization is understood to be the primary route for cross-linking. As polymer chains cross-link, mechanical properties, such as for example the Young's modulus, the film hardness, the fracture toughness and the interfacial adhesion, are improved, thereby improving the fabrication robustness of the low-k film.

[0006] As there are various strategies to forming porous dielectric films with ultra low dielectric constant, the objectives of post-deposition treatments (curing) may vary from film to film, including for example the removal of moisture, the removal of solvents, the burn-out of porogens used to form the pores in the porous dielectric film, the improvement of the mechanical properties for such films, and so on.

[0007] Low dielectric constant (low k) materials are conventionally thermally cured at a temperature in the range of 300 °C to 400 °C for CVD films. For instance, furnace curing has been sufficient in producing strong, dense low-k films with a dielectric constant greater than approximately 2.5. However, when processing porous dielectric films (such as ultra low-k films) with a high level of porosity, the degree of cross-linking achievable with thermal treatment (or thermal curing) is no longer sufficient to produce films of adequate strength for a robust interconnect structure.

[0008] During thermal curing, an appropriate amount of energy is delivered to the dielectric film without damaging the dielectric film. Within the temperature

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range of interest, however, only a small amount of free radicals can be generated. Only a small amount of thermal energy can actually be absorbed in the low-k films to be cured due to the thermal energy lost in the coupling of heat to the substrate and the heat loss in the ambient environment. Therefore, high temperatures and long curing times are required for typical low-k furnace curing. But even with a high thermal budget, the lack of initiator generation in the thermal curing and the presence of a large amount of methyl termination in the as-deposited low-k film can make it very difficult to achieve the desired degree of cross-linking.

SUMMARY OF THE INVENTION

[0009] The invention relates to a method for treating a dielectric film and, more particularly, to a method of curing a low dielectric constant (low-k) dielectric film.

[0010] According to an embodiment, a method of, and computer readable medium for, curing a low dielectric constant (low-k) dielectric film on a substrate is described, wherein the dielectric constant of the low-k dielectric film is less than a value of approximately 4. The method comprises exposing the low-k dielectric film to ultraviolet (UV) radiation. Following the UV exposure, the dielectric film is exposed to IR radiation.

BRIEF DESCRIPTION OF THE DRAWINGS

[0011] In the accompanying drawings:

[0012] FIG. 1 is a flow chart of a method of treating a dielectric film according to an embodiment;

[0013] FIG. 2 provides exemplary data for treating a dielectric film;

[0014] FIGs. 3A through 3C are schematic representations of a transfer system for a drying system and a curing system according to an embodiment;

[0015] FIG. 4 is a schematic cross-sectional view of a drying system according to another embodiment; and

[0016] FIG. 5 is a schematic cross-sectional view of a curing system according to another embodiment.

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DETAILED DESCRIPTION OF EXEMPLARY EMBODIMENTS

[0017] In the following description, in order to facilitate a thorough understanding of the invention and for purposes of explanation and not limitation, specific details are set forth, such as a particular geometry of the processing system and descriptions of various components and processes. However, it should be understood that the invention may be practiced in other embodiments that depart from these specific details.

[0018] The inventors recognized that alternative curing methods address some of the deficiencies of thermal curing alone. For instance, alternative curing methods are more efficient in energy transfer, as compared to thermal curing processes, and the higher energy levels found in the form of energetic particles, such as accelerated electrons, ions, or neutrals, or in the form of energetic photons, can easily excite electrons in a low-k film, thus efficiently breaking chemical bonds and dissociating side groups. These alternative curing methods facilitate the generation of cross-linking initiators (free radicals) and can improve the energy transfer required in actual cross-linking. As a result, the degree of cross-linking can be increased at a reduced thermal budget.

[0019] Additionally, the inventors have realized that, as film strength becomes a greater issue for the integration of low-k and ultra-low-k (ULK) dielectric films (dielectric constant less than approximately 2.5), alternative curing methods can improve the mechanical properties of such films. For example, electron beam (EB), ultraviolet (UV) radiation, infrared (IR) radiation and microwave (MW) radiation may be used to cure low-k films and ULK films in order to improve mechanical strength, while not sacrificing the dielectric property and film hydrophobicity.

[0020] However, although EB, UV, IR and MW curing all have their own benefits, these techniques also have limitations. High energy curing sources such as EB and UV can provide high energy levels to generate more than enough free radicals for cross-linking, which leads to much improved mechanical properties under complementary substrate heating. On the other hand, electrons and UV photons can cause indiscriminate dissociation of chemical bonds, which may adversely degrade the desired physical and electrical properties of the film, such as loss of hydrophobicity, increased

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residual film stress, collapse of pore structure, film densification and increased dielectric constant. Furthermore, low energy curing sources, such as IR and MW curing, can provide significant improvements mostly in the heat transfer efficiency, but in the meantime have side effects, such as for example skin layer or surface densification (IR), and arcing or transistor damage (MW).

[0021] According to an embodiment, a method of curing a low dielectric constant (low-k) dielectric film on a substrate is described, wherein the dielectric constant of the low-k dielectric film is less than a value of approximately 4. The method comprises exposing the low-k dielectric film to ultraviolet (UV) radiation. Following the UV exposure, the dielectric film is exposed to infrared (IR) radiation.

[0022] During the UV exposure, the low-k dielectric film may be heated by elevating the temperature of the substrate to a cure temperature ranging from approximately 200 degrees C to approximately 600 degrees C. Alternatively, the cure temperature ranges from approximately 300 degrees C to approximately 500 degrees C. Further, during the UV exposure, the low-k dielectric film may be exposed to IR radiation.

[0023] Following the UV exposure, the low-k dielectric film may be heated by elevating the temperature of the substrate to a thermal treatment temperature ranging from approximately 200 degrees C to approximately 600 degrees C. Alternatively, the thermal treatment temperature ranges from approximately 300 degrees C to approximately 500 degrees C and, desirably, the thermal treatment temperature ranges from approximately 350 degrees C to approximately 450 degrees C.

[0024] Referring now to FIG. 1, a method of treating a dielectric film on a substrate is described according to another embodiment. The substrate, to be treated, may be a semiconductor, a metallic conductor, or any other substrate to which the dielectric film is to be formed upon. The dielectric film can have a dielectric constant value (before drying and/or curing, or after drying and/or curing, or both) less than the dielectric constant of SiO₂, which is approximately 4 (e.g., the dielectric constant for thermal silicon dioxide can range from 3.8 to 3.9). In various embodiments of the invention, the dielectric film may have a dielectric constant (before drying and/or curing, or after drying

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and/or curing, or both) of less than 3.0, a dielectric constant of less than 2.5, or a dielectric constant ranging from 1.6 to 2.7.

[0025] The dielectric film may be described as a low dielectric constant (low-k) film or an ultra-low-k film. The dielectric film may, for instance, include a dual phase porous low-k film which may have a higher dielectric constant prior to porogen burn-out than following porogen burn-out. Additionally, the dielectric film may have moisture and/or other contaminants which cause the dielectric constant to be higher prior to drying and/or curing than following drying and/or curing.

[0026] The dielectric film can be formed using chemical vapor deposition (CVD) techniques, or spin-on dielectric (SOD) techniques such as those offered in the Clean Track ACT 8 SOD and ACT 12 SOD coating systems commercially available from Tokyo Electron Limited (TEL). The Clean Track ACT 8 (200 mm) and ACT 12 (300 mm) coating systems provide coat, bake, and cure tools for SOD materials. The track system can be configured for processing substrate sizes of 100 mm, 200 mm, 300 mm, and greater. Other systems and methods for forming a dielectric film on a substrate as known to those skilled in the art of both spin-on dielectric technology and CVD dielectric technology are suitable for the invention.

[0027] The dielectric film can, for example, be characterized as a low dielectric constant (or low-k) dielectric film. The dielectric film may include at least one of an organic, inorganic, and inorganic-organic hybrid material. Additionally, the dielectric film may be porous or non-porous. For example, the dielectric film may include an inorganic, silicate-based material, such as oxidized organosilane (or organo siloxane), deposited using CVD techniques. Examples of such films include Black Diamond™ CVD organosilicate glass (OSG) films commercially available from Applied Materials, Inc., or Coral™ CVD films commercially available from Novellus Systems. Additionally, for example, porous dielectric films can include single-phase materials, such as a silicon oxide-based matrix having terminal organic side groups that inhibit cross-linking during a curing process to create small voids (or pores). Additionally, for example, porous dielectric films can include dual-phase materials, such as a silicon oxide-based matrix having inclusions of organic material (e.g., a porogen) that is decomposed and evaporated during a curing

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process. Alternatively, the dielectric film may include an inorganic, silicate-based material, such as hydrogen silsesquioxane (HSQ) or methyl silsesquioxane (MSQ), deposited using SOD techniques. Examples of such films include FOx HSQ commercially available from Dow Corning, XLK porous HSQ commercially available from Dow Corning, and JSR LKD-5109 commercially available from JSR Microelectronics. Still alternatively, the dielectric film can include an organic material deposited using SOD techniques. Examples of such films include SiLK-I, SiLK-J, SiLK-H, SiLK-D, porous SiLK-T, porous SiLK-Y, and porous SiLK-Z semiconductor dielectric resins commercially available from Dow Chemical, and FLARE™, and Nanoglass commercially available from Honeywell.

[0028] The method includes a flow chart 500 beginning in 510 with optionally drying the dielectric film on the substrate in a first processing system. The first processing system may include a drying system configured to remove, or partially remove, one or more contaminants in the dielectric film, including, for example, moisture, solvent, porogen, or any other contaminant that may interfere with a subsequent curing process.

[0029] In 520, the dielectric film is exposed to UV radiation. The UV-assisted curing of the dielectric film may be performed in a second processing system. The second processing system may include a curing system configured to perform a UV-assisted cure of the dielectric film by causing or partially causing cross-linking within the dielectric film in order to, for example, improve the mechanical properties of the dielectric film. Following the drying process, the substrate can be transferred from the first processing system to the second processing system under vacuum in order to minimize contamination.

[0030] The exposure of the dielectric film to UV radiation may include exposing the dielectric film to UV radiation from one or more UV lamps, one or more UV LEDs (light-emitting diodes), or one or more UV lasers, or a combination of two or more thereof. The UV radiation may range in wavelength from approximately 100 nanometers to approximately 600 nanometers. Desirably, the UV radiation may range in wavelength from approximately 200 nanometers to approximately 400 nanometers and, more desirably, the UV radiation may range in wavelength from approximately 200 nanometers to approximately 300 nanometers.

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[0031] During the exposure of the dielectric film to UV radiation, the dielectric film may be heated by elevating the temperature of the substrate to a cure temperature ranging from approximately 200 degrees C to approximately 600 degrees C. Alternatively, the cure temperature can range from approximately 300 degrees C to approximately 500 degrees C.

[0032] Optionally, during the exposure of the dielectric film to UV radiation, the dielectric film may be exposed to IR radiation. The exposure of the dielectric film to IR radiation may include exposing the dielectric film to IR radiation from one or more IR lamps, one or more IR LEDs (light emitting diodes), or one or more IR lasers, or a combination of two or more thereof. The IR radiation may range in wavelength from approximately 1 micron to approximately 25 microns. Desirably, the IR radiation may range in wavelength from approximately 8 microns to approximately 14 microns.

[0033] In 530, following the UV exposure, the dielectric film is exposed to IR radiation. The exposure of the dielectric film to IR radiation may include exposing the dielectric film to IR radiation from one or more IR lamps, one or more IR LEDs (light emitting diodes), or one or more IR lasers, or both. The IR radiation may range in wavelength from approximately 1 micron to approximately 25 microns. Desirably, the IR radiation may range in wavelength from approximately 8 microns to approximately 14 microns.

[0034] Furthermore, during the IR exposure, the dielectric film may be heated by elevating the temperature of the substrate to a thermal treatment temperature ranging from approximately 200 degrees C to approximately 600 degrees C. Alternatively, the thermal treatment temperature can range from approximately 300 degrees C to approximately 500 degrees C. Alternatively yet, the thermal treatment temperature can range from approximately 350 degrees C to approximately 550 degrees C.

[0035] As described above, during the IR exposure, the dielectric film may be heated through absorption of IR energy. However, the heating may further include conductively heating the substrate by placing the substrate on a substrate holder, and heating the substrate holder using a heating device. For example, the heating device may include a resistive heating element.

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[0036] The inventors have recognized that the energy level ($h\nu$) delivered and the rate that energy is delivered to the dielectric film (q') varies during different stages of the curing process. The curing process can include mechanisms for generation of cross-link initiators, burn-out of porogens, decomposition of porogens, film cross-linking, and optionally cross-link initiator diffusion. Each mechanism may require a different energy level and rate at which energy is delivered to the dielectric film.

[0037] For instance, during the curing of the matrix material, cross-link initiators may be generated using photon and phonon induced bond dissociation within the matrix material. Bond dissociation can require energy levels having a wavelength less than or equal to approximately 300 to 400 nm. Additionally, for instance, porogen burn-out may be facilitated with photon absorption by the photosensitizer. Porogen burn-out may require UV wavelengths, such as wavelengths less than or equal to approximately 300 to 400 nm.

[0038] Further yet, for instance, cross-linking can be facilitated by thermal energy sufficient for bond formation and reorganization. Bond formation and reorganization may require energy levels having a wavelength of approximately 9 microns which, for example, corresponds to the main absorbance peak in siloxane-based organosilicate low-k materials.

[0039] The IR exposure of the dielectric film, following the UV exposure, may be performed in the same processing system as the UV exposure, i.e., the second processing system. Alternatively, the IR exposure of the dielectric film, following the UV exposure, may be performed in a different processing system than the UV exposure. For example, the IR exposure of the dielectric film may be performed in a third processing system, wherein the substrate can be transferred from the second processing system to the third processing system under vacuum in order to minimize contamination.

[0040] Additionally, following the optional drying process, the UV exposure process, and the IR exposure process, the dielectric film may optionally be post-treated in a post-treatment system configured to modify the cured dielectric film. For example, post-treatment can include spin coating or vapor depositing another film on the dielectric film in order to promote adhesion for

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subsequent films or improve hydrophobicity. Alternatively, for example, adhesion promotion may be achieved in a post-treatment system by lightly bombarding the dielectric film with ions. Moreover, the post-treatment may comprise performing one or more of depositing another film on the dielectric film, cleaning the dielectric film, or exposing the dielectric film to plasma.

[0041] Referring now to FIG. 2, exemplary data is provided for treating a dielectric film. The dielectric film comprises a porous dielectric film including dual-phase materials that is formed using a chemical vapor deposition (CVD) process. As illustrated in FIG. 2, the refractive index is presented for several substrates, wherein each substrate has a dielectric film formed thereon which is to be cured by exposing the dielectric film to UV radiation at 266 nm. The refractive index is provided for a pristine dielectric film, i.e., prior to curing (open bar), and it is provided for the corresponding cured dielectric film (cross-hatched bar). As shown in FIG. 2, the curing process causes a reduction of the refractive index, thus, indicating the removal of the second-phase constituent and the formation of pores.

[0042] Referring still to FIG. 2, the refractive index (for pristine and cured films) is provided for four (4) substrates where no additional heating of the dielectric film is performed, either before or after the curing process (i.e., "No additional thermal treatment"). Additionally, the refractive index (for pristine and cured films) is provided for five (5) substrates where the dielectric film is heated prior to the curing process (i.e., "Pre-cure thermal treatment"). Furthermore, the refractive index (for pristine and cured films) is provided for four (4) substrates where the dielectric film is heated following the curing process (i.e., "Post-cure thermal treatment"). In the latter two scenarios, when the dielectric film undergoes either pre-cure treatment or post-cure treatment, the dielectric film is exposed to IR radiation at approximately 9.4 microns. As shown in FIG. 2, either pre-heating or post-heating the dielectric film causes a reduction in the refractive index (relative to no additional heating), which may indicate a more effective process for the removal of the second-phase constituent. Moreover, post-heating the dielectric film causes further reduction in the refractive index relative to pre-heating.

[0043] While the wavelength or wave-band for the IR radiation and the temperature are important parameters for performing the thermal treatment

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process, the time for the thermal treatment process is also important. The inventor has observed that the dependence on post-heating temperature and time may be indicative of a diffusion-controlled process that drives the out-diffusion of second-phase constituent (e.g., porogen) residue(s).

[0044] According to one embodiment, FIG. 3A shows a processing system 1 for treating a dielectric film on a substrate, according to one embodiment. The processing system 1 includes a drying system 10, and a curing system 20 coupled to the drying system 10. For example, the drying system 10 can be configured to remove, or reduce to sufficient levels, one or more contaminants in the dielectric film, including, for example, moisture, solvent, porogen, or any other contaminant that may interfere with a curing process performed in the curing system 20.

[0045] For example, a sufficient reduction of a specific contaminant present within the dielectric film, from prior to the drying process to following the drying process, can include a reduction of approximately 10% to approximately 100% of the specific contaminant. The level of contaminant reduction may be measured using Fourier transform infrared (FTIR) spectroscopy, or mass spectroscopy. Alternatively, for example, a sufficient reduction of a specific contaminant present within the dielectric film can range from approximately 50% to approximately 100%. Alternatively, for example, a sufficient reduction of a specific contaminant present within the dielectric film can range from approximately 80% to approximately 100%.

[0046] Referring still to FIG. 3A, the curing system 20 may be configured to cure the dielectric film by causing or partially causing cross-linking within the dielectric film in order to, for example, improve the mechanical properties of the dielectric film. Furthermore, the curing system 20 may be configured to cure the dielectric film by causing or partially causing cross-link initiation, porogen burn-out, porogen decomposition, etc. The curing system 20 can include one or more radiation sources configured to expose the substrate having the dielectric film to electro-magnetic (EM) radiation at multiple EM wavelengths. For example, the one or more radiation sources can include an infrared (IR) radiation source and an optional ultraviolet (UV) radiation source. The exposure of the substrate to UV radiation and optional IR radiation can be performed simultaneously, sequentially, or over-lapping one another. During

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sequential exposure, the exposure of the substrate to UV radiation can, for instance, precede the exposure of the substrate to IR radiation or vice versa.

[0047] For example, the IR radiation can include an IR wave-band source ranging from approximately 1 micron to approximately 25 microns and, desirably, ranging from approximately 8 microns to approximately 14 microns. Additionally, for example, the UV radiation can include a UV wave-band source producing radiation ranging from approximately 100 nanometers (nm) to approximately 600 nm and, desirably, ranging from approximately 200 nm to approximately 400 nm.

[0048] Also, as illustrated in FIG. 3A, a transfer system 30 can be coupled to the drying system 10 in order to transfer substrates into and out of the drying system 10 and the curing system 20, and exchange substrates with a multi-element manufacturing system 40. Transfer system 30 may transfer substrates to and from drying system 10 and curing system 20 while maintaining a vacuum environment. The drying and curing systems 10, 20, and the transfer system 30 can, for example, include a processing element within the multi-element manufacturing system 40. For example, the multi-element manufacturing system 40 can permit the transfer of substrates to and from processing elements including such devices as etch systems, deposition systems, coating systems, patterning systems, metrology systems, etc. In order to isolate the processes occurring in the first and second systems, an isolation assembly 50 can be utilized to couple each system. For instance, the isolation assembly 50 can include at least one of a thermal insulation assembly to provide thermal isolation, and a gate valve assembly to provide vacuum isolation. The drying and curing systems 10 and 20, and transfer system 30 can be placed in any sequence.

[0049] As described above, the IR exposure of the substrate can be performed in the drying system 10, or the curing system 20, or a separate treatment system (not shown).

[0050] Alternately, in another embodiment of the invention, FIG. 3B shows a processing system 100 for treating a dielectric film on a substrate. The processing system 100 includes a "cluster-tool" arrangement for a drying system 110, and a curing system 120. For example, the drying system 110 can be configured to remove, or reduce to sufficient levels, one or more

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contaminants in the dielectric film, including, for example, moisture, solvent, porogen, or any other contaminant that may interfere with a curing process performed in the curing system 120. Additionally, for example, the curing system 120 can be configured to cure the dielectric film by causing or partially causing cross-linking within the dielectric film in order to, for example, improve the mechanical properties of the dielectric film. Furthermore, the processing system 100 can optionally include a post-treatment system 140 configured to modify the cured dielectric film. For example, post-treatment can include spin coating or vapor depositing another film on the dielectric film in order to promote adhesion for subsequent films or improve hydrophobicity. Alternatively, for example, adhesion promotion may be achieved in a post-treatment system by lightly bombarding the dielectric film with ions by, for example, exposing the substrate to plasma.

[0051] Also, as illustrated in FIG. 3B, a transfer system 130 can be coupled to the drying system 110 in order to transfer substrates into and out of the drying system 110, and can be coupled to the curing system 120 in order to transfer substrates into and out of the curing system 120, and can be coupled to the optional post-treatment system 140 in order to transfer substrates into and out of the post-treatment system 140. Transfer system 130 may transfer substrates to and from drying system 110, curing system 120 and optional post-treatment system 140 while maintaining a vacuum environment.

[0052] Additionally, transfer system 130 can exchange substrates with one or more substrate cassettes (not shown). Although only two or three process systems are illustrated in FIG. 3B, other process systems can access transfer system 130 including for example such devices as etch systems, deposition systems, coating systems, patterning systems, metrology systems, etc. In order to isolate the processes occurring in the drying and curing systems, an isolation assembly 150 can be utilized to couple each system. For instance, the isolation assembly 150 can include at least one of a thermal insulation assembly to provide thermal isolation, and a gate valve assembly to provide vacuum isolation. Additionally, for example, the transfer system 130 can serve as part of the isolation assembly 150.

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[0053] As described above, the IR exposure of the substrate can be performed in the drying system 110, or the curing system 120, or a separate treatment system (not shown).

[0054] Alternately, in another embodiment of the invention, FIG. 3C shows a processing system 200 for treating a dielectric film on a substrate. The processing system 200 includes a drying system 210, and a curing system 220. For example, the drying system 210 can be configured to remove, or reduce to sufficient levels, one or more contaminants in the dielectric film, including, for example, moisture, solvent, porogen, or any other contaminant that may interfere with a curing process performed in the curing system 220. Additionally, for example, the curing system 220 can be configured to cure the dielectric film by causing or partially causing cross-linking within the dielectric film in order to, for example, improve the mechanical properties of the dielectric film. Furthermore, the processing system 200 can optionally include a post-treatment system 240 configured to modify the cured dielectric film. For example, post-treatment can include spin coating or vapor depositing another film on the dielectric film in order to promote adhesion for subsequent films or improve hydrophobicity. Alternatively, for example, adhesion promotion may be achieved in a post-treatment system by lightly bombarding the dielectric film with ions by, for example, exposing the substrate to plasma.

[0055] Drying system 210, curing system 220, and post-treatment system 240 can be arranged horizontally or may be arranged vertically (i.e., stacked). Also, as illustrated in FIG. 3C, a transfer system 230 can be coupled to the drying system 210 in order to transfer substrates into and out of the drying system 210, can be coupled to the curing system 220 in order to transfer substrates into and out of the curing system 220, and can be coupled to the optional post-treatment system 240 in order to transfer substrates into and out of the post-treatment system 240. Transfer system 230 may transfer substrates to and from drying system 210, curing system 220 and optional post-treatment system 240 while maintaining a vacuum environment.

[0056] Additionally, transfer system 230 can exchange substrates with one or more substrate cassettes (not shown). Although only three process systems are illustrated in FIG. 3C, other process systems can access transfer system 230 including for example such devices as etch systems, deposition

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systems, coating systems, patterning systems, metrology systems, etc. In order to isolate the processes occurring in the first and second systems, an isolation assembly 250 can be utilized to couple each system. For instance, the isolation assembly 250 can include at least one of a thermal insulation assembly to provide thermal isolation, and a gate valve assembly to provide vacuum isolation. Additionally, for example, the transfer system 230 can serve as part of the isolation assembly 250.

[0057] As described above, the IR exposure of the substrate can be performed in the drying system 210, or the curing system 220, or a separate treatment system (not shown).

[0058] At least one of the drying system 10 and the curing system 20 of the processing system 1 as depicted in FIG. 3A includes at least two transfer openings to permit the passage of the substrate therethrough. For example, as depicted in FIG. 3A, the drying system 10 includes two transfer openings, the first transfer opening permits the passage of the substrate between the drying system 10 and the transfer system 30 and the second transfer opening permits the passage of the substrate between the drying system and the curing system. However, regarding the processing system 100 depicted in FIG. 3B and the processing system 200 depicted in FIG. 3C, each treatment system 110, 120, 140 and 210, 220, 240, respectively, includes at least one transfer opening to permit the passage of the substrate therethrough.

[0059] Referring now to FIG. 4, a drying system 300 is shown according to another embodiment of the invention. Drying system 300 includes a drying chamber 310 configured to produce a clean, contaminant-free environment for drying a substrate 325 resting on substrate holder 320. The drying system 300 can include a thermal treatment device 330 coupled to drying chamber 310, or to substrate holder 320, and configured to evaporate contaminants, such as for example moisture, residual solvent, etc., by elevating the temperature of substrate 325. Furthermore, the drying system 300 can include a microwave treatment device 340 coupled to the drying chamber 310, and configured to locally heat contaminants in the presence of an oscillating electric field. The drying process can utilize the thermal treatment device 330, or the microwave treatment device 340, or both to facilitate drying a dielectric film on substrate 325.

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[0060] The thermal treatment device 330 can include one or more conductive heating elements embedded in substrate holder 320 coupled to a power source and a temperature controller. For example, each heating element can include a resistive heating element coupled to a power source configured to supply electrical power. Alternatively, the thermal treatment device 330 can include one or more radiative heating elements coupled to a power source and a controller. For example, each radiative heating element can include a heat lamp coupled to a power source configured to supply electrical power. The temperature of substrate 325 can, for example, range from approximately 20 °C to approximately 500 °C, and desirably, the temperature may range from approximately 200 °C to approximately 400 °C.

[0061] The microwave treatment source 340 can include a variable frequency microwave source configured to sweep the microwave frequency through a bandwidth of frequencies. Frequency variation avoids charge build-up and, hence, permits damage-free application of microwave drying techniques to sensitive electronic devices.

[0062] In one example, the drying system 300 can include a drying system incorporating both a variable frequency microwave device and a thermal treatment device, such as for example the microwave furnace commercially available from Lambda Technologies, Inc. (860 Aviation Parkway, Suite 900, Morrisville, NC 27560).

[0063] The substrate holder 320 may or may not be configured to clamp substrate 325. For instance, substrate holder 320 may be configured to mechanically or electrically clamp substrate 325.

[0064] Referring again to FIG. 4, drying system 300 can further include a gas injection system 350 coupled to the drying chamber and configured to introduce a purge gas to drying chamber 310. The purge gas can, for example, include an inert gas, such as a noble gas or nitrogen. Additionally, drying system 300 can include a vacuum pumping system 355 coupled to drying chamber 310 and configured to evacuate the drying chamber 310. During a drying process, substrate 325 can be subject to an inert gas environment with or without vacuum conditions.

[0065] Furthermore, drying system 300 can include a controller 360 coupled to drying chamber 310, substrate holder 320, thermal treatment device 330,

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microwave treatment device 340, gas injection system 350, and vacuum pumping system 355. Controller 360 includes a microprocessor, a memory, and a digital I/O port capable of generating control voltages sufficient to communicate and activate inputs to the drying system 300 as well as monitor outputs from the drying system 300. A program stored in the memory is utilized to interact with the drying system 300 according to a stored process recipe. The controller 360 can be used to configure any number of processing elements (310, 320, 330, 340, 350, or 355), and the controller 360 can collect, provide, process, store, and display data from processing elements. The controller 360 can include a number of applications for controlling one or more of the processing elements. For example, controller 360 can include a graphic user interface (GUI) component (not shown) that can provide interfaces that enable a user to monitor and/or control one or more processing elements.

[0066] Referring now to FIG. 5, a curing system 400 is shown according to another embodiment of the present invention. Curing system 400 includes a curing chamber 410 configured to produce a clean, contaminant-free environment for curing a substrate 425 resting on substrate holder 420. Curing system 400 further includes one or more radiation sources configured to expose substrate 425 having the dielectric film to electro-magnetic (EM) radiation at single, multiple, narrow-band, or broadband EM wavelengths. The one or more radiation sources can include an optional infrared (IR) radiation source 440 and an ultraviolet (UV) radiation source 445. The exposure of the substrate to UV radiation and optionally IR radiation can be performed simultaneously, sequentially, or over-lapping one another.

[0067] The IR radiation source 440 may include a broad-band IR source, or may include a narrow-band IR source. The IR radiation source may include one or more IR lamps, one or more IR LEDs, or one or more IR lasers (continuous wave (CW), tunable, or pulsed), or any combination thereof. The IR power may range from approximately 0.1 mW to approximately 2000 W. The IR radiation wavelength may range from approximately 1 micron to approximately 25 microns and, desirably, can range from approximately 8 microns to approximately 14 microns. For example, the IR radiation source 440 may include an IR element, such as a ceramic element or silicon carbide

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element, having a spectral output ranging from approximately 1 micron to approximately 25 microns, or the IR radiation source 440 can include a semiconductor laser (diode), or ion, Ti:sapphire, or dye laser with optical parametric amplification.

[0068] The UV radiation source 445 may include a broad-band UV source, or may include a narrow-band UV source. The UV radiation source may include one or more UV lamps, one or more UV LEDs, or one or more UV lasers (continuous wave (CW), tunable, or pulsed), or any combination thereof. UV radiation may be generated, for instance, from a microwave source, an arc discharge, a dielectric barrier discharge, or electron impact generation. The UV power density may range from approximately 0.1 mW/cm² to approximately 2000 mW/cm². The UV wavelength may range from approximately 100 nanometers (nm) to approximately 600 nm and, desirably, may range from approximately 200 nm to approximately 400 nm. For example, the UV radiation source 445 may include a direct current (DC) or pulsed lamp, such as a Deuterium (D₂) lamp, having a spectral output ranging from approximately 180 nm to approximately 500 nm, or the UV radiation source 445 may include a semiconductor laser (diode), (nitrogen) gas laser, frequency-tripled Nd:YAG laser, or copper vapor laser.

[0069] The IR radiation source 440, or the UV radiation source 445, or both, may include any number of optical device to adjust one or more properties of the output radiation. For example, each source may further include optical filters, optical lenses, beam expanders, beam collimators, etc. Such optical manipulation devices as known to those skilled in the art of optics and EM wave propagation are suitable for the invention.

[0070] The substrate holder 420 can further include a temperature control system that can be configured to elevate and/or control the temperature of substrate 425. The temperature control system can be a part of a thermal treatment device 430. The substrate holder 420 can include one or more conductive heating elements embedded in substrate holder 420 coupled to a power source and a temperature controller. For example, each heating element can include a resistive heating element coupled to a power source configured to supply electrical power. The substrate holder 420 could optionally include one or more radiative heating elements. The temperature

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of substrate 425 can, for example, range from approximately 20 °C to approximately 500 °C, and desirably, the temperature may range from approximately 200 °C to approximately 400 °C.

[0071] Additionally, the substrate holder 420 may or may not be configured to clamp substrate 425. For instance, substrate holder 420 may be configured to mechanically or electrically clamp substrate 425.

[0072] Referring again to FIG. 5, curing system 400 can further include a gas injection system 450 coupled to the curing chamber 410 and configured to introduce a purge gas to curing chamber 410. The purge gas can, for example, include an inert gas, such as a noble gas or nitrogen. Alternatively, the purge gas can include other gases, such as for example H₂, NH₃, C_xH_y, or any combination thereof. Additionally, curing system 400 can further include a vacuum pumping system 455 coupled to curing chamber 410 and configured to evacuate the curing chamber 410. During a curing process, substrate 425 can be subject to a purge gas environment with or without vacuum conditions.

[0073] Furthermore, curing system 400 can include a controller 460 coupled to drying chamber 410, substrate holder 420, thermal treatment device 430, IR radiation source 440, UV radiation source 445, gas injection system 450, and vacuum pumping system 455. Controller 460 includes a microprocessor, a memory, and a digital I/O port capable of generating control voltages sufficient to communicate and activate inputs to the curing system 400 as well as monitor outputs from the curing system 400. A program stored in the memory is utilized to interact with the curing system 400 according to a stored process recipe. The controller 460 can be used to configure any number of processing elements (410, 420, 430, 440, 445, 450, or 455), and the controller 460 can collect, provide, process, store, and display data from processing elements. The controller 460 can include a number of applications for controlling one or more of the processing elements. For example, controller 460 can include a graphic user interface (GUI) component (not shown) that can provide easy to use interfaces that enable a user to monitor and/or control one or more processing elements.

[0074] The controllers 360 and 460 may be implemented as a DELL PRECISION WORKSTATION 610™. The controllers 360 and 460 may also

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be implemented as a general purpose computer, processor, digital signal processor, etc., which causes a substrate processing apparatus to perform a portion or all of the processing steps of the invention in response to the controllers 360 and 460 executing one or more sequences of one or more instructions contained in a computer readable medium. The computer readable medium or memory for holding instructions programmed according to the teachings of the invention and for containing data structures, tables, records, or other data described herein. Examples of computer readable media are compact discs, hard disks, floppy disks, tape, magneto-optical disks, PROMs (EPROM, EEPROM, flash EPROM), DRAM, SRAM, SDRAM, or any other magnetic medium, compact discs (e.g., CD-ROM), or any other optical medium, punch cards, paper tape, or other physical medium with patterns of holes, a carrier wave (described below), or any other medium from which a computer can read.

[0075] The controllers 360 and 460 may be locally located relative to the drying system 300 and curing system 400, or may be remotely located relative to the drying system 300 and curing system 400 via an internet or intranet. Thus, the controllers 360 and 460 can exchange data with the drying system 300 and curing system 400 using at least one of a direct connection, an intranet, and the internet. The controllers 360 and 460 may be coupled to an intranet at a customer site (i.e., a device maker, etc.), or coupled to an intranet at a vendor site (i.e., an equipment manufacturer). Furthermore, another computer (i.e., controller, server, etc.) can access controllers 360 and 460 to exchange data via at least one of a direct connection, an intranet, and the internet.

[0076] Furthermore, embodiments of this invention may be used as or to support a software program executed upon some form of processing core (such as a processor of a computer, e.g., controller 360 or 460) or otherwise implemented or realized upon or within a machine-readable medium. A machine-readable medium includes any mechanism for storing information in a form readable by a machine (e.g., a computer). For example, a machine-readable medium can include such as a read only memory (ROM); a random access memory (RAM); a magnetic disk storage media; an optical storage media; and a flash memory device, etc.

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[0077] Although only certain exemplary embodiments of this invention have been described in detail above, those skilled in the art will readily appreciate that many modifications are possible in the exemplary embodiments without materially departing from the novel teachings and advantages of this invention. Accordingly, all such modifications are intended to be included within the scope of this invention.

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WHAT IS CLAIMED IS:

1. A method of curing a low dielectric constant (low-k) dielectric film on a substrate, comprising:

disposing a substrate having a low-k dielectric film in a curing system;
exposing said low-k dielectric film to ultraviolet (UV) radiation in said curing system; and

following said UV exposure, exposing said low-k dielectric film to infrared (IR) radiation,

wherein the dielectric constant of said low-k dielectric film is less than a value of approximately 4.

2. The method of claim 1, further comprising:

during said IR exposure, heating said low-k dielectric film by elevating the temperature of said substrate to a thermal treatment temperature ranging from approximately 200 degrees C to approximately 600 degrees C.

3. The method of claim 2, wherein said thermal treatment temperature ranges from approximately 350 degrees C to approximately 450 degrees C.

4. The method of claim 1, further comprising:

during said UV exposure, heating said low-k dielectric film by elevating the temperature of said substrate to a cure temperature ranging from approximately 200 degrees C to approximately 600 degrees C.

5. The method of claim 4, wherein said cure temperature ranges from approximately 300 degrees C to approximately 500 degrees C.

6. The method of claim 1, wherein said IR exposure is performed in a process system different from said curing system.

7. The method of claim 1, wherein said exposing said dielectric film to UV radiation comprises exposing said dielectric film to UV radiation from one

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or more UV lamps, one or more UV LEDs, or one or more UV lasers, or a combination of two or more thereof.

8. The method of claim 1, wherein said exposing said dielectric film to UV radiation comprises exposing said dielectric film to UV radiation with a wavelength ranging from approximately 100 nanometers to approximately 600 nanometers.

9. The method of claim 1, wherein said exposing said dielectric film to UV radiation comprises exposing said dielectric film to UV radiation with a wavelength ranging from approximately 200 nanometers to approximately 400 nanometers.

10. The method of claim 1, wherein said exposing said dielectric film to IR radiation comprises exposing said dielectric film to IR radiation from one or more IR lamps, one or more IR LEDs, or one or more IR lasers, or a combination of two or more thereof.

11. The method of claim 1, wherein said exposing said dielectric film to IR radiation comprises exposing said dielectric film to IR radiation with a wavelength ranging from approximately 1 micron to approximately 25 microns.

12. The method of claim 1, wherein said exposing said dielectric film to IR radiation comprises exposing said dielectric film to IR radiation with a wavelength ranging from approximately 8 microns to approximately 14 microns.

13. The method of claim 1, wherein said exposing said dielectric film to UV radiation further comprises:

 exposing said dielectric film to IR radiation during at least a portion of said UV exposure.

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14. The method of claim 13, wherein said exposing said dielectric film to IR radiation comprises exposing said dielectric film to IR radiation ranging from approximately 8 microns to approximately 14 microns.

15. The method of claim 1, further comprising:
prior to said UV exposure, disposing said substrate in a drying system;
drying said dielectric film according to a drying process in order to remove or partially remove contaminants on or in said dielectric film; and
transferring said substrate from said drying system to said curing system while maintaining vacuum conditions during said transfer.

16. The method of claim 1, further comprising:
treating said dielectric film following said IR exposure by performing one or more of depositing another film on said dielectric film, cleaning said dielectric film, or exposing said dielectric film to plasma.

17. The method of claim 1, wherein the dielectric constant of said low-k dielectric film is less than or equal to a value of approximately 2.5.

18. The method of claim 17, wherein said low-k dielectric film comprises an inorganic dielectric film, an organic dielectric film, a hybrid organic-inorganic dielectric film, a porous dielectric film, or a non-porous dielectric film, or a combination of two or more thereof.

19. The method of claim 1, wherein said low-k dielectric film comprises a siloxane-based organosilicate low-k material, and wherein said UV radiation includes a wavelength ranging from about 200 nm to about 300 nm and said IR radiation includes a wavelength ranging from about 9 microns to about 10 microns.

20. A computer readable medium containing program instructions for execution on a control system, which when executed by the control system, cause a curing system to perform the steps of:

disposing a substrate having a low-k dielectric film in a curing system;

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exposing said low-k dielectric film to ultraviolet (UV) radiation in said curing system; and

following said UV exposure, exposing said low-k dielectric film to infrared (IR) radiation,

wherein the dielectric constant of said low-k dielectric film is less than a value of approximately 4.

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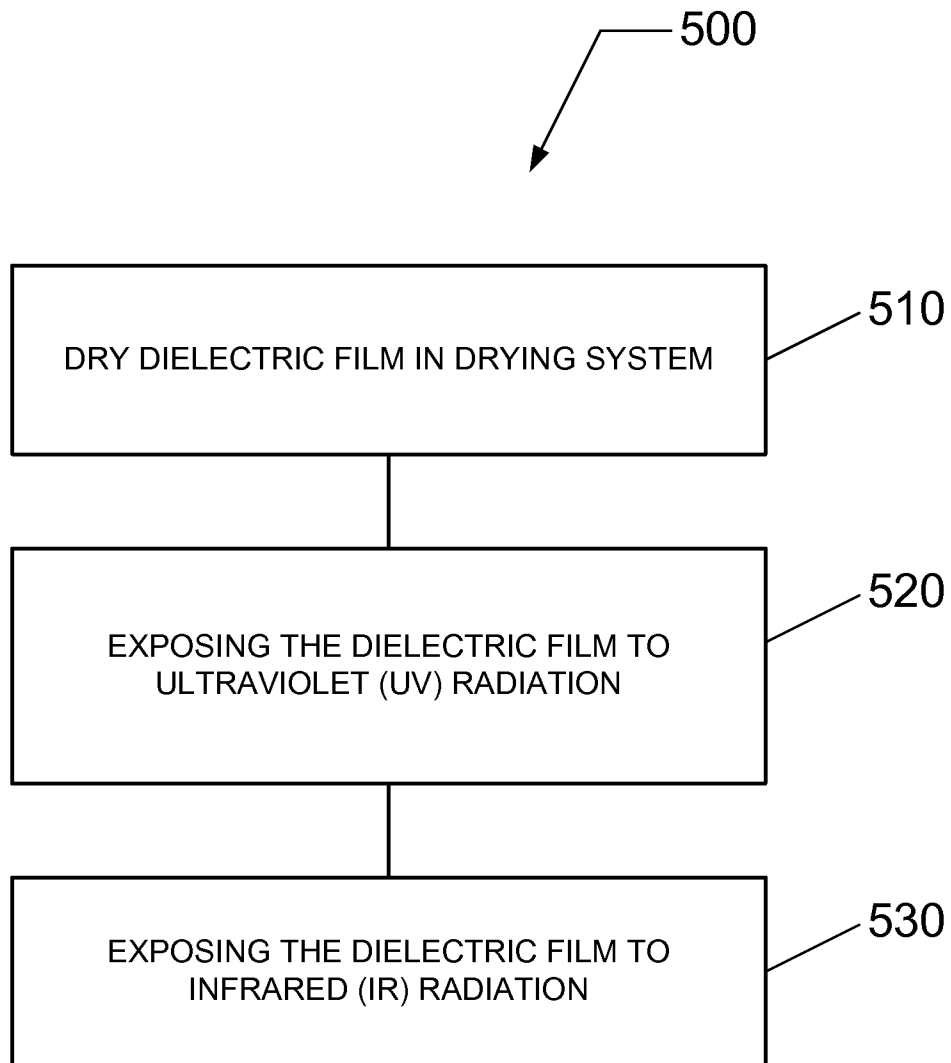


FIG. 1

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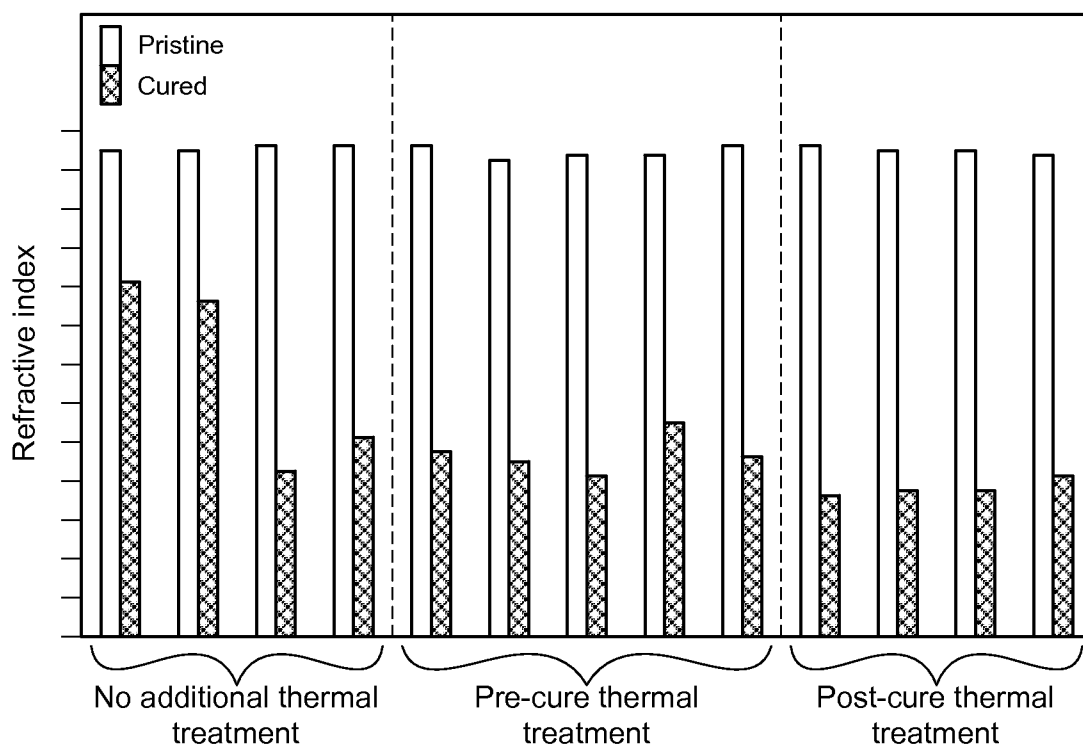


FIG. 2

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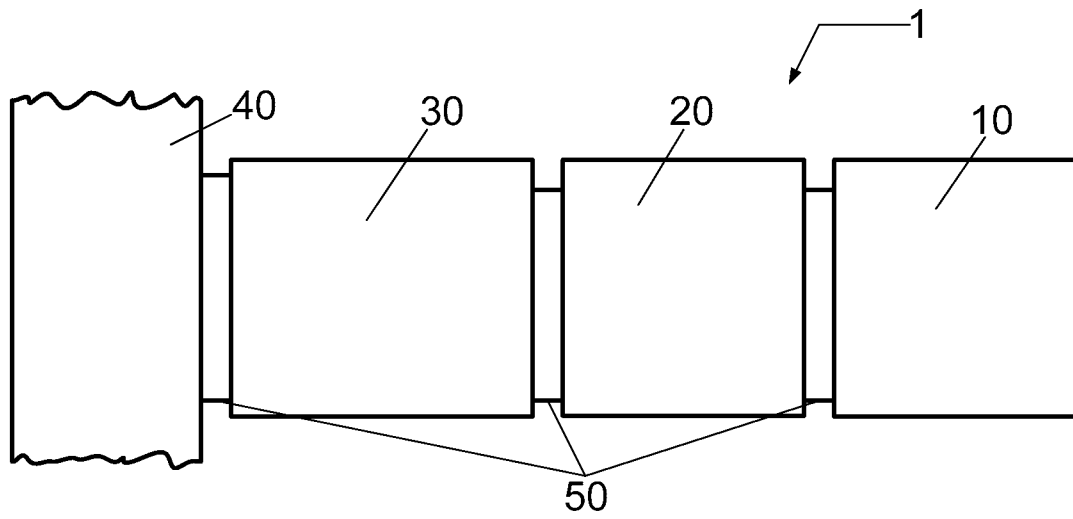


FIG. 3A

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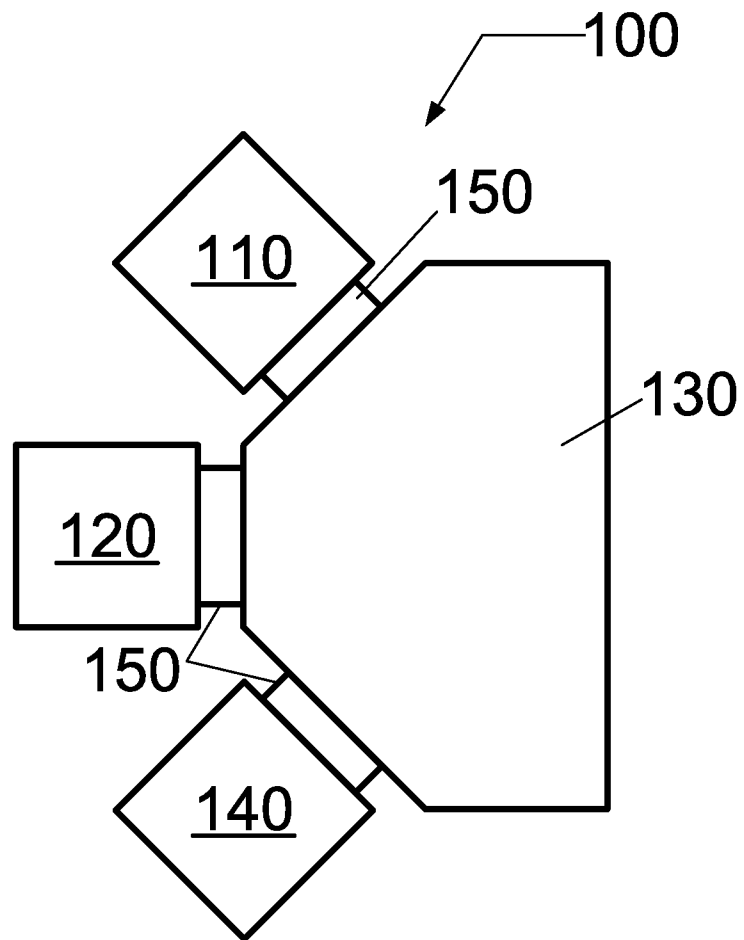


FIG. 3B

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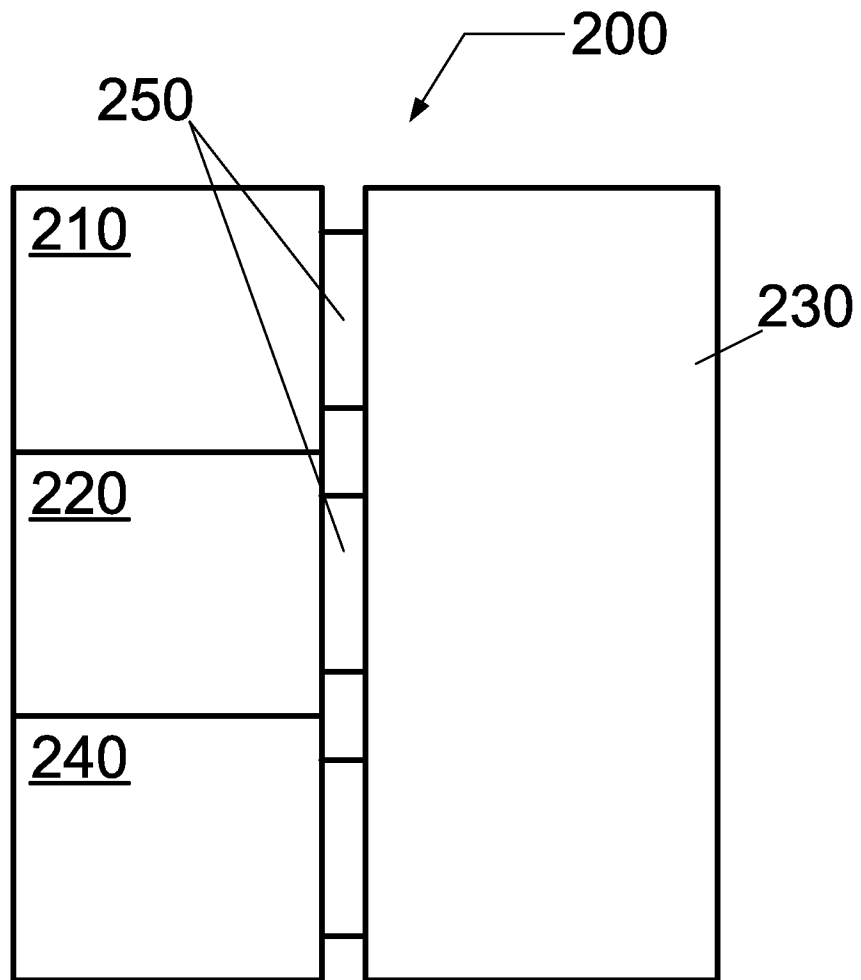


FIG. 3C

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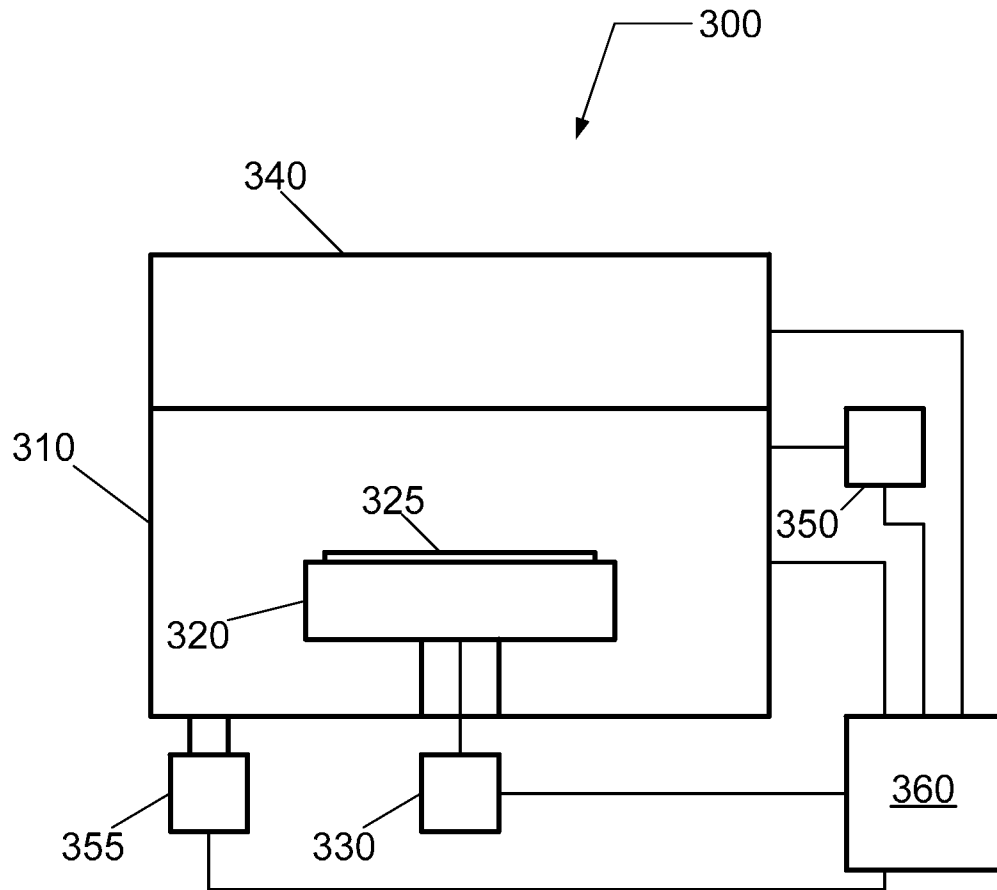


FIG. 4

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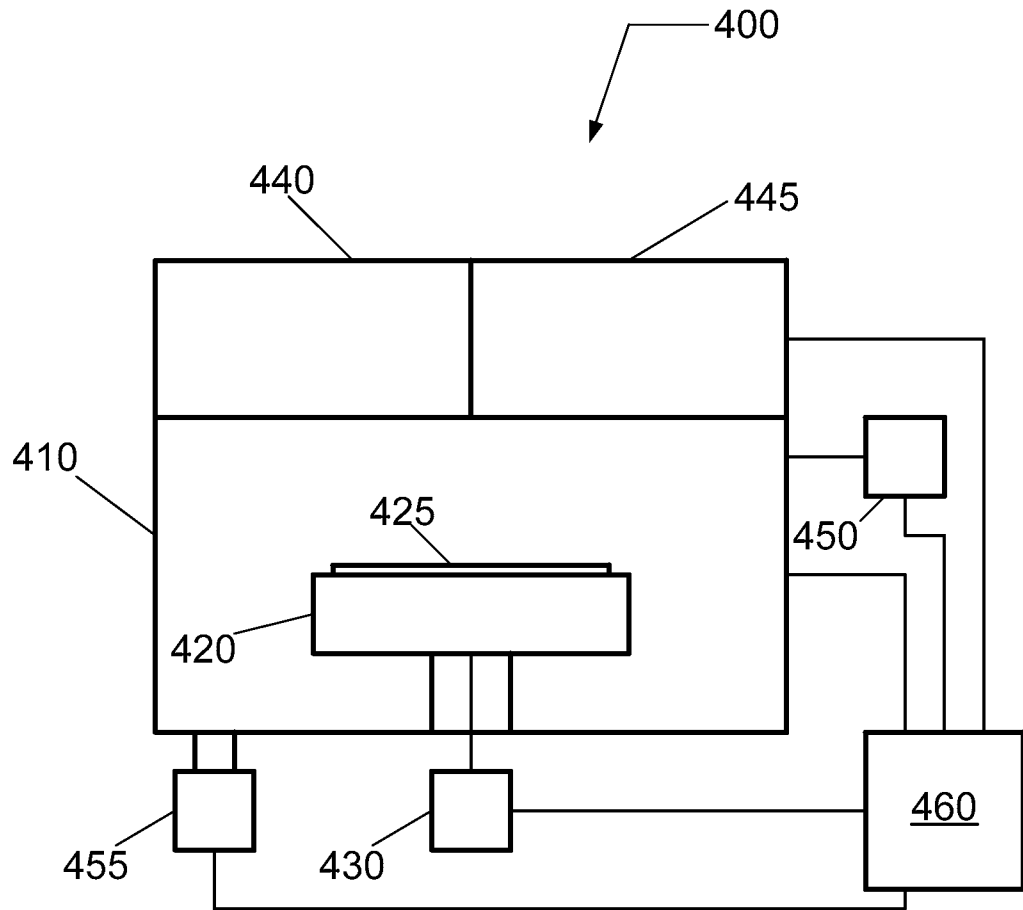


FIG. 5

INTERNATIONAL SEARCH REPORT

International application No.

PCT/US08/76134

A. CLASSIFICATION OF SUBJECT MATTER

IPC: H01L 21/00(2006.01)

USPC: 438/800;257/E21.001

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

U.S. : 438/800,758,770; 257/E21.001; 118/724

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched
NONE

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)
Please See Continuation Sheet

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X,P ---	US 2008/0063809 A1 (LEE et al.) 13 March 2008 (13.03.2008), see entire document.	1-5,7-20
Y,P		6
Y	US 2005/0085094 A1 (YOO) 21 April 2005 (21.04.2005), see entire document.	6

☐ Further documents are listed in the continuation of Box C.

☐ See patent family annex.

* Special categories of cited documents:

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier application or patent published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T"

later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X"

document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y"

document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&"

document member of the same patent family

Date of the actual completion of the international search

30 October 2008 (30.10.2008)

Date of mailing of the international search report

03 NOV 2008

Name and mailing address of the ISA/US

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INTERNATIONAL SEARCH REPORT

International application No.
PCT/US08/76134

Continuation of B. FIELDS SEARCHED Item 3:

USPGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB search notes: ((ultraviolet or UV) adj (cur\$3 or treat\$4)),
((infrared or IR) adj (cut\$3 or treat\$4)), (low\$1k adj (dielectric or material or film)), dielectric